

Yasuo Cho

List of Publications by Year in descending order

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157
docs citations

157
times ranked

2105
citing authors

#	ARTICLE	IF	CITATIONS
1	Boxcar Averaging Scanning Nonlinear Dielectric Microscopy. <i>Nanomaterials</i> , 2022, 12, 794.	4.1	1
2	Carrier profile mapping in a 3D Flash memory cell using scanning nonlinear dielectric microscopy. , 2022, , .		0
3	Local capacitance-voltage profiling on MoS ₂ /SiO ₂ and MoS ₂ /h-BN/SiO ₂ by scanning nonlinear dielectric microscopy assisted with an insulating tip. , 2022, , .		0
4	Local capacitance-voltage profiling and deep level transient spectroscopy of SiO ₂ /SiC interfaces by scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2022, 135, 114588.	1.7	2
5	Material Design Strategy for Enhancement of Readback Signal Intensity in Ferroelectric Probe Data Storage. <i>IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control</i> , 2021, 68, 859-864.	3.0	1
6	Local C-V Characterization for Ferroelectric Films. , 2021, , .		0
7	High-precision local C-V mapping for ferroelectrics using principal component analysis. <i>Japanese Journal of Applied Physics</i> , 2021, 60, SFFB09.	1.5	1
8	Local capacitance-voltage profiling and high voltage stress effect study of SiO ₂ /SiC structures by time-resolved scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2021, 126, 114284.	1.7	3
9	Nanoscale capacitance-voltage profiling of DC bias induced stress on a high- κ /SiO ₂ /Si gate stack. <i>Microelectronics Reliability</i> , 2021, 126, 114278.	1.7	1
10	Local Capacitance-Voltage Profiling and Deep Level Transient Spectroscopy of SiO ₂ /SiC Interfaces by Scanning Nonlinear Dielectric Microscopy. , 2021, , .		1
11	Simulation of nanoscale domain growth for ferroelectric recording. <i>AIP Advances</i> , 2021, 11, 115117.	1.3	0
12	Effects of deposition conditions on the ferroelectric properties of (Al _{1-x} Sc _x)N thin films. <i>Journal of Applied Physics</i> , 2020, 128, .	2.5	127
13	Nanoscale characterization of unintentional doping of atomically thin layered semiconductors by scanning nonlinear dielectric microscopy. <i>Journal of Applied Physics</i> , 2020, 128, .	2.5	4
14	Spatial scale dependent impact of non-uniform interface defect distribution on field effect mobility in SiC MOSFETs. <i>Microelectronics Reliability</i> , 2020, 114, 113829.	1.7	4
15	Profiling of carriers in a 3D flash memory cell with nanometer-level resolution using scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2020, 114, 113774.	1.7	4
16	Sample collection from asteroid (162173) Ryugu by Hayabusa2: Implications for surface evolution. <i>Science</i> , 2020, 368, 654-659.	12.6	158
17	Carrier distribution measurement in semiconductor materials and devices. , 2020, , 153-174.		0
18	A scanning nonlinear dielectric microscopic investigation of potential-induced degradation in monocrystalline silicon solar cells. <i>Applied Physics Letters</i> , 2020, 116, 182107.	3.3	1

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19	Linear permittivity measurement by scanning nonlinear dielectric microscopy. , 2020, , 75-94.		0
20	Noncontact scanning nonlinear dielectric microscopy. , 2020, , 95-112.		2
21	Principles of scanning nonlinear dielectric microscopy for semiconductor measurement. , 2020, , 141-151.		0
22	Super-higher-order scanning nonlinear dielectric microscopy. , 2020, , 175-188.		0
23	Local deep-level transient spectroscopy. , 2020, , 189-219.		0
24	Time-resolved scanning nonlinear dielectric microscopy. , 2020, , 221-238.		0
25	Local $\text{C}\hat{=}\text{V}$ mapping for ferroelectrics using scanning nonlinear dielectric microscopy. Journal of Applied Physics, 2020, 128, 244105.	2.5	4
26	Carrier distribution imaging using $\hat{=}\text{C}/\hat{=}\text{z}$ -mode scanning nonlinear dielectric microscopy. Review of Scientific Instruments, 2019, 90, 083705.	1.3	1
27	Boxcar Averaging Based Scanning Nonlinear Dielectric Microscopy and Its Application to Carrier Distribution Imaging on 2D Semiconductors. , 2019, , .		4
28	High Resolution Mapping of Defects at SiO_2/SiC Interfaces by Local-DLTS Based on Time-Resolved Scanning Nonlinear Dielectric Microscopy. , 2019, , .		0
29	A Study on Evaluation of Interface Defect Density on High-K/ SiO_2 / Si and SiO_2 / Si Gate Stacks using Scanning Nonlinear Dielectric Microscopy. , 2019, , .		4
30	Spatially-Resolved Evaluation of Interface Defect Density on Macrostepped SiO_2/SiC using Local Deep Level Transient Spectroscopy. , 2019, , .		0
31	Optimization of signal intensity in intermittent contact scanning nonlinear dielectric microscopy. Microelectronics Reliability, 2019, 100-101, 113345.	1.7	3
32	Two-dimensional defect mapping of the SiO_2/SiC interface. Physical Review Materials, 2019, 3, .	2.4	5
33	Nanoscale linear permittivity imaging based on scanning nonlinear dielectric microscopy. Nanotechnology, 2018, 29, 205709.	2.6	4
34	High resolution observation of defects at $\text{SiO}_2/4\text{H-SiC}$ interfaces using time-resolved scanning nonlinear dielectric microscopy. Microelectronics Reliability, 2018, 88-90, 242-245.	1.7	4
35	Quantitative Imaging of MOS Interface Trap Distribution by Using Local Deep Level Transient Spectroscopy. , 2018, , .		0
36	Visualization of traps at SiO_2/SiC interfaces near the conduction band by local deep level transient spectroscopy at low temperatures. Japanese Journal of Applied Physics, 2018, 57, 08NB12.	1.5	4

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37	Scanning probe-type data storage beyond hard disk drive and flash memory. MRS Bulletin, 2018, 43, 365-370.	3.5	11
38	Improvement of Local Deep Level Transient Spectroscopy for Microscopic Evaluation of SiO ₂ /4H-SiC Interfaces. Materials Science Forum, 2018, 924, 289-292.	0.3	0
39	Local carrier distribution imaging on few-layer MoS ₂ exfoliated on SiO ₂ by scanning nonlinear dielectric microscopy. Applied Physics Letters, 2018, 112, .	3.3	6
40	Local deep level transient spectroscopy using super-higher-order scanning nonlinear dielectric microscopy and its application to imaging two-dimensional distribution of SiO ₂ /SiC interface traps. Journal of Applied Physics, 2017, 122, .	2.5	21
41	Dynamic observation of ferroelectric domain switching using scanning nonlinear dielectric microscopy. Japanese Journal of Applied Physics, 2017, 56, 10PF16.	1.5	4
42	High resolution characterizations of fine structure of semiconductor device and material using scanning nonlinear dielectric microscopy. Japanese Journal of Applied Physics, 2017, 56, 100101.	1.5	22
43	Evaluation of silicon- and carbon-face SiO ₂ /SiC MOS interface quality based on scanning nonlinear dielectric microscopy. Applied Physics Letters, 2017, 111, .	3.3	13
44	Quantitative measurement of active dopant density distribution in phosphorus-implanted monocrystalline silicon solar cell using scanning nonlinear dielectric microscopy. Applied Physics Letters, 2017, 111, .	3.3	15
45	Nanosecond microscopy of capacitance at SiO ₂ /4H-SiC interfaces by time-resolved scanning nonlinear dielectric microscopy. Applied Physics Letters, 2017, 111, .	3.3	23
46	Introduction of Scanning Nonlinear Dielectric Microscopy and Its Applications to the Evaluation of Electronic Materials and Devices. Journal of the Institute of Electrical Engineers of Japan, 2017, 137, 697-700.	0.0	0
47	Simultaneous observation of two dimensional electron gas and polarization in AlGaN/GaN heterostructure using scanning nonlinear dielectric microscopy. Japanese Journal of Applied Physics, 2016, 55, 08NB13.	1.5	6
48	High-density ferroelectric recording using a hard disk drive-type data storage system. Journal of Applied Physics, 2016, 119, .	2.5	16
49	Two-dimensional analysis of carrier distribution in phosphorus-implanted emitter and phosphorus-diffused emitter using super-higher-order scanning nonlinear dielectric microscopy. , 2016, , .		1
50	Local deep level transient spectroscopy using super-higher-order scanning nonlinear dielectric microscopy. Microelectronics Reliability, 2016, 64, 566-569.	1.7	8
51	Visualization of Gate-Bias-Induced Carrier Redistribution in SiC Power DIMOSFET Using Scanning Nonlinear Dielectric Microscopy. IEEE Transactions on Electron Devices, 2016, 63, 3165-3170.	3.0	8
52	site-driven ferroelectricity in strained ferromagnetic $\text{La}_2\text{NiMnO}_6$ thin films.	3.2	42
53	Phy Interfacial Charge States in Graphene on SiC Studied by Noncontact Scanning Nonlinear Dielectric Potentiometry. Physical Review Letters, 2015, 114, 226103.	7.8	31
54	Scanning nonlinear dielectric potentiometry. Review of Scientific Instruments, 2015, 86, 093704.	1.3	18

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55	Experimental study of electric dipoles on an oxygen-adsorbed Si(100)-2 \times 1 surface by non-contact scanning nonlinear dielectric microscopy. Applied Physics Letters, 2015, 107, 031604.	3.3	2
56	Visualization and analysis of active dopant distribution in a p-i-n structured amorphous silicon solar cell using scanning nonlinear dielectric microscopy. AIP Advances, 2015, 5, .	1.3	7
57	Interfacial capacitance between a ferroelectric Fe ₃ O ₄ thin film and a semiconducting Nb:SrTiO ₃ substrate. Journal of Applied Physics, 2015, 117, 014104.	2.5	12
58	Pb(Zr,Ti)O ₃ recording media for probe data storage devices prepared by rf magnetron sputtering. Japanese Journal of Applied Physics, 2014, 53, 09PA05.	1.5	6
59	Improved study of electric dipoles on the Si(100)-2 \times 1 surface by non-contact scanning nonlinear dielectric microscopy. Applied Physics Letters, 2014, 105, 101603.	3.3	7
60	Cross-sectional dopant profiling and depletion layer visualization of SiC power double diffused metal-oxide-semiconductor field effect transistor using super-higher-order nonlinear dielectric microscopy. Journal of Applied Physics, 2014, 116, .	2.5	32
61	Atomic-dipole-moment induced local surface potential on Si(111)-(7 \times 7) surface studied by non-contact scanning nonlinear dielectric microscopy. Applied Physics Letters, 2014, 105, 121601.	3.3	5
62	Charge gradient microscopy. Proceedings of the National Academy of Sciences of the United States of America, 2014, 111, 6566-6569.	7.1	44
63	Atomic dipole moment distribution on a hydrogen-adsorbed Si(111)-(7 \times 7) surface observed by noncontact scanning nonlinear dielectric microscopy. Applied Physics Letters, 2013, 103, .	3.3	10
64	Measurements of Nonlinear Dielectric Constants of Pb(Zr,Ti)O ₃ Thin Films Using a Dynamic Measuring Method. Japanese Journal of Applied Physics, 2013, 52, 09KA08.	1.5	4
65	High resolution imaging in cross-section of a metal-oxide-semiconductor field-effect-transistor using super-higher-order nonlinear dielectric microscopy. Journal of Physics: Conference Series, 2013, 471, 012023.	0.4	1
66	Lateral resolution improvement in scanning nonlinear dielectric microscopy by measuring super-higher-order nonlinear dielectric constants. Applied Physics Letters, 2012, 101, .	3.3	14
67	Scanning nonlinear dielectric microscopy observation of accumulated charges in metal-SiO ₂ -SiN-SiO ₂ -Si flash memory by detecting higher-order nonlinear permittivity. Applied Physics Letters, 2012, 101, 242101.	3.3	4
68	New evaluation of fullerene molecules on Si(111)-(7 \times 7) reconstructed structure using non-contact scanning non-linear dielectric microscopy. Surface Science, 2012, 606, 174-180.	1.9	3
69	Observation of Nanoscale Ferroelectric Domains Using Super-Higher-Order Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2012, 51, 09LE07.	1.5	2
70	Scanning nonlinear dielectric microscopy. Journal of Materials Research, 2011, 26, 2007-2016.	2.6	40
71	Observation of dopant profile of transistors using scanning nonlinear dielectric microscopy. Journal of Physics: Conference Series, 2010, 209, 012050.	0.4	8
72	Intermittent contact scanning nonlinear dielectric microscopy. Review of Scientific Instruments, 2010, 81, 023705.	1.3	7

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73	Investigation of interface between fullerene molecule and Si(111)-7 \times 7 surface by noncontact scanning nonlinear dielectric microscopy. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2010, 28, C4D18-C4D23.	1.2	9
74	Observation of electrochemical capacitance in a graphite surface by noncontact scanning nonlinear dielectric microscopy. Physical Review B, 2010, 82, .	3.2	9
75	Actual information storage with a recording density of 4 \times Tbit/in. ² in a ferroelectric recording medium. Applied Physics Letters, 2010, 97, 092901.	3.3	35
76	Characterization and comparison of nanoscale domain boundary in congruent and stoichiometric LiTaO ₃ with scanning nonlinear dielectric microscopy. Applied Physics Letters, 2009, 95, 022908.	3.3	3
77	Nanodomain Formation on Ferroelectrics and Development of Hard-Disk-Drive-Type Ferroelectric Data Storage Devices. Japanese Journal of Applied Physics, 2009, 48, 09KA18.	1.5	14
78	Scanning Nonlinear Dielectric Microscopy Nano-Science and Technology for Next Generation High Density Ferroelectric Data Storage. Japanese Journal of Applied Physics, 2008, 47, 3311.	1.5	73
79	Multiferroism at Room Temperature in BiFeO ₃ /BiCrO ₃ (111) Artificial Superlattices. Applied Physics Express, 2008, 1, 101302.	2.4	33
80	The influence of 180 \times ferroelectric domain wall width on the threshold field for wall motion. Journal of Applied Physics, 2008, 104, 084107.	2.5	53
81	Observations of Domain Structure and Ferroelectricity in Bi(Ni _{0.5} Ti _{0.5})O ₃ Ceramics Fabricated by High-pressure Sintering. Chemistry Letters, 2008, 37, 560-561.	1.3	8
82	Observation of the Si(111)7 \times 7 atomic structure using non-contact scanning nonlinear dielectric microscopy. Nanotechnology, 2007, 18, 084014.	2.6	31
83	Cross-sectional observation of nanodomain dots formed in both congruent and stoichiometric LiTaO ₃ crystals. Applied Physics Letters, 2007, 90, 192906.	3.3	19
84	Novel HDD-type SNDM ferroelectric data storage system aimed at high-speed data transfer with single probe operation. IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control, 2007, 54, 2523-2528.	3.0	9
85	Dielectric Moment Distribution of Si Atoms on a Si(111)7 \times 7 Surface. Applied Physics Letters, 2007, 91, 092901.	7.8	52
86	Scanning Nonlinear Dielectric Microscope with Super High Resolution. Japanese Journal of Applied Physics, 2007, 46, 4428.	1.5	12
87	Visualization of charges stored in the floating gate of flash memory by scanning nonlinear dielectric microscopy. Nanotechnology, 2006, 17, S185-S188.	2.6	32
88	Nanodomain manipulation for ultrahigh density ferroelectric data storage. Nanotechnology, 2006, 17, S137-S141.	2.6	79
89	Three-dimensional observation of nanoscale ferroelectric domains using scanning nonlinear dielectric microscopy with electric field correction by Kelvin probe force microscopy. Nanotechnology, 2006, 17, S162-S166.	2.6	8
90	Piezoelectric Performance and Domain Structure of Epitaxial PbTiO ₃ Thin Film Deposited by Hydrothermal Method. Japanese Journal of Applied Physics, 2006, 45, 4489-4492.	1.5	20

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91	Piezoelectric property of an epitaxial lead titanate thin film deposited by the hydrothermal method. Applied Physics Letters, 2006, 88, 112908.	3.3	29
92	Wall behavior of nanodomains as a function of their initial state. Applied Physics Letters, 2006, 89, 192906.	3.3	18
93	Three-Dimensional Measurement for Absolute Value of Polarization Angle by Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2005, 44, 4325-4329.	1.5	6
94	Non-contact scanning nonlinear dielectric microscopy. Nanotechnology, 2005, 16, S54-S58.	2.6	42
95	Visualization of electrons and holes localized in the thin gate film of metal-oxide-nitride-oxide-semiconductor type Flash memory by scanning nonlinear dielectric microscopy. Nanotechnology, 2005, 16, S90-S93.	2.6	15
96	Visualization of electrons and holes localized in gate thin film of metal SiO ₂ /Si ₃ N ₄ /SiO ₂ semiconductor-type flash memory using scanning nonlinear dielectric microscopy after writing-erasing cycling. Applied Physics Letters, 2005, 86, 063515.	3.3	20
97	Realization of 10Tbit/in. ² memory density and subnanosecond domain switching time in ferroelectric data storage. Applied Physics Letters, 2005, 87, 232907.	3.3	69
98	Visualization using scanning nonlinear dielectric microscopy of electrons and holes localized in the thin gate film of a metal SiO ₂ /Si ₃ N ₄ /SiO ₂ semiconductor flash memory. Applied Physics Letters, 2005, 86, 013501.	3.3	21
99	Epitaxial PbTiO ₃ Thin Films on SrTiO ₃ (100) and SrRuO ₃ /SrTiO ₃ (100) Substrates Deposited by a Hydrothermal Method. Japanese Journal of Applied Physics, 2004, 43, 6535-6538.	1.5	34
100	Evaluation of Bit Error Rate for Ferroelectric Data Storage. Japanese Journal of Applied Physics, 2004, 43, 6632-6634.	1.5	17
101	Polarization reversal anti-parallel to the applied electric field observed using a scanning nonlinear dielectric microscopy. Applied Physics Letters, 2004, 84, 257-259.	3.3	39
102	Domain structure in a micron-sized PbZr _{1-x} Ti _x O ₃ single crystal on a Ti substrate fabricated by hydrothermal synthesis. Applied Physics Letters, 2004, 84, 3346-3348.	3.3	33
103	Effect of the surface adsorbed water on the studying of ferroelectrics by scanning nonlinear dielectric microscopy. Journal of Applied Physics, 2004, 96, 7460-7463.	2.5	23
104	A hydrothermally deposited epitaxial lead titanate thin film on strontium ruthenium oxide bottom electrode. Applied Physics Letters, 2004, 85, 2331-2333.	3.3	45
105	Ferroelectric property of an epitaxial lead zirconate titanate thin film deposited by a hydrothermal method. Journal of Materials Research, 2004, 19, 1862-1868.	2.6	32
106	Nanosecond Switching of Nanoscale Ferroelectric Domains in Congruent Single-Crystal LiTaO ₃ Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2004, 43, 2818-2821.	1.5	14
107	Ferroelectric properties of an epitaxial lead zirconate titanate thin film deposited by a hydrothermal method below the Curie temperature. Applied Physics Letters, 2004, 84, 5094-5096.	3.3	52
108	Observation of domain walls in PbZr _{0.2} Ti _{0.8} O ₃ thin film using scanning nonlinear dielectric microscopy. Applied Physics Letters, 2003, 83, 2650-2652.	3.3	28

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109	Terabit inch ² ferroelectric data storage using scanning nonlinear dielectric microscopy nanodomain engineering system. <i>Nanotechnology</i> , 2003, 14, 637-642.	2.6	40
110	High-speed switching of nanoscale ferroelectric domains in congruent single-crystal LiTaO ₃ . <i>Applied Physics Letters</i> , 2003, 83, 5265-5267.	3.3	40
111	Microscale to nanoscale ferroelectric domain and surface engineering of a near-stoichiometric LiNbO ₃ crystal. <i>Applied Physics Letters</i> , 2003, 82, 433-435.	3.3	117
112	Ultrahigh-Density Ferroelectric Data Storage Using Scanning Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2003, 42, 6050-6054.	1.5	23
113	Scanning nonlinear dielectric microscopy. <i>Advances in Imaging and Electron Physics</i> , 2003, 127, 1-57.	0.2	3
114	Measuring ferroelectric polarization component parallel to the surface by scanning nonlinear dielectric microscopy. <i>Applied Physics Letters</i> , 2002, 80, 2159-2161.	3.3	21
115	Tbit/inch ² ferroelectric data storage based on scanning nonlinear dielectric microscopy. <i>Applied Physics Letters</i> , 2002, 81, 4401-4403.	3.3	186
116	Quantitative Measurement of Linear Dielectric Constant Using Scanning Nonlinear Dielectric Microscopy with Electro-Conductive Cantilever. <i>Japanese Journal of Applied Physics</i> , 2002, 41, 4961-4964.	1.5	16
117	Development of scanning microwave microscope with a lumped-constant resonator probe for high-throughput characterization of combinatorial dielectric materials. <i>Applied Surface Science</i> , 2002, 189, 222-226.	6.1	25
118	Scanning-nonlinear-dielectric-microscopy study on periodically poled LiNbO ₃ for a high-performance quasi-phase matching device. <i>Applied Physics Letters</i> , 2001, 79, 2955-2957.	3.3	22
119	Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy. <i>Journal of the European Ceramic Society</i> , 2001, 21, 1581-1584.	5.7	3
120	Single crystal growth of KNbO ₃ and application to surface acoustic wave devices. <i>Journal of the European Ceramic Society</i> , 2001, 21, 2791-2795.	5.7	30
121	New Functions of Scanning Nonlinear Dielectric Microscopy "Higher-Order Measurement and Vertical Resolution". <i>Japanese Journal of Applied Physics</i> , 2001, 40, 3544-3548.	1.5	12
122	Measurement of the Ferroelectric Domain Distributions Using Nonlinear Dielectric Response and Piezoelectric Response. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 3534-3537.	1.5	29
123	Fundamental Study of Surface Layer on Ferroelectrics by Scanning Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 5833-5836.	1.5	10
124	Characterization of Ferroelectric Property of C-Axis- and Non-C-Axis-Oriented Epitaxially Grown Bi ₂ VO _{5.5} Thin Films. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 6481-6486.	1.5	19
125	Higher Order Nonlinear Dielectric Imaging Using Scanning Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 4349-4353.	1.5	12
126	Fundamental Study on Nano Domain Engineering Using Scanning Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 4354-4356.	1.5	14

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127	Simultaneous Observation of Ferroelectric Domain Patterns by Scanning Nonlinear Dielectric Microscope and Surface Morphology by Atomic Force Microscope. Japanese Journal of Applied Physics, 2000, 39, 3808-3810.	1.5	22
128	Quantitative Measurement of Linear and Nonlinear Dielectric Characteristics Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2000, 39, 3086-3089.	1.5	33
129	Theoretical and Experimental Study on Nanoscale Ferroelectric Domain Measurement Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2000, 39, 5719-5722.	1.5	54
130	Determination of the Polarities of ZnO Thin Films on Polar and Nonpolar Substrates Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2000, 39, 3121-3124.	1.5	21
131	Determination of Electrostrictive and Third-Order Dielectric Constants of Piezoelectric Ceramic. Japanese Journal of Applied Physics, 2000, 39, 3524-3527.	1.5	3
132	Simultaneous observation of nano-sized ferroelectric domains and surface morphology using scanning nonlinear dielectric microscopy. Surface Science, 2000, 463, L621-L625.	1.9	64
133	Observation of Ultrathin Single-Domain Layers Formed on LiTaO ₃ and LiNbO ₃ Surfaces Using Scanning Nonlinear Dielectric Microscope with Submicron Resolution. Japanese Journal of Applied Physics, 1999, 38, 3279-3282.	1.5	23
134	Scanning Nonlinear Dielectric Microscopy with Contact Sensing Mechanism for Observation of Nanometer Sized Ferroelectric Domains. Japanese Journal of Applied Physics, 1999, 38, 5689-5694.	1.5	26
135	Determination of the Temperature Coefficient Distribution of Dielectric Ceramics Using Scanning Photothermal Dielectric Microscopy. Journal of the American Ceramic Society, 1999, 82, 1720-1724.	3.8	3
136	Scanning nonlinear dielectric microscopy with nanometer resolution. Applied Physics Letters, 1999, 75, 2833-2835.	3.3	177
137	Scanning Nonlinear Dielectric Microscope Using a Lumped Constant Resonator Probe and Its Application to Investigation of Ferroelectric Polarization Distributions. Japanese Journal of Applied Physics, 1997, 36, 3152-3156.	1.5	78
138	Observation of Ferroelectric Polarization in the Noncontact Mode of a Scanning Nonlinear Dielectric Microscope. Japanese Journal of Applied Physics, 1997, 36, 360-363.	1.5	12
139	New microscope for measuring the distribution of nonlinear dielectric properties. Electronics and Communications in Japan, 1996, 79, 68-75.	0.2	4
140	Photothermal dielectric spectroscopic microscope. Review of Scientific Instruments, 1996, 67, 19-28.	1.3	13
141	Scanning nonlinear dielectric microscope. Review of Scientific Instruments, 1996, 67, 2297-2303.	1.3	243
142	Active control of nonlinear piezoelectric effect and its application to 20 dB efficiency improvement of SAW elastic convolver. , 1994, , .		2
143	Experimental demonstration of the reduction of the number of independent electrostrictive constants of piezoelectric ceramics. , 1994, , .		0
144	Relations between the constants of electrostrictive materials and some examples of their application to piezoelectric ceramics. Electronics and Communications in Japan, Part III: Fundamental Electronic Science (English Translation of Denshi Tsushin Gakkai Ronbunshi), 1993, 76, 20-30.	0.1	0

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145	Dynamic measurement of nonlinear constants of PZT ceramics. Electronics and Communications in Japan, Part III: Fundamental Electronic Science (English Translation of Denshi Tsushin Gakkai) Tj ETQq1 1 0.7843140gBT /Overclock 10	0.784314	10
146	Surface acoustic wave soliton propagating on the metallic grating waveguide. Applied Physics Letters, 1993, 63, 1188-1190.	3.3	29
147	Influence of Rare Earth Ions on BaO-TiO ₂ -Rare Earth Oxide Ceramics for Microwave Applications. Japanese Journal of Applied Physics, 1993, 32, 1712-1715.	1.5	28
148	Dynamic method for measuring the velocity variation of ultrasound in piezoelectric ceramics with an alternating electric field. Review of Scientific Instruments, 1993, 64, 1244-1247.	1.3	12
149	Dynamic Measuring Method of Capacitance Variation of Piezoelectric Ceramics with Alternating Electric Field. Japanese Journal of Applied Physics, 1992, 31, 3627-3631.	1.5	31
150	Nonlinear, elastic, piezoelectric, electrostrictive, and dielectric constants of lithium niobate. Journal of Applied Physics, 1987, 61, 875-887.	2.5	146
151	Scanning nonlinear dielectric microscope for investigation of polarization distributions. , 0, , .		0
152	Microscopic observation of the temperature coefficient distribution of dielectric material for microwave application using scanning photothermal dielectric microscope. , 0, , .		0
153	Influence of Non-Uniform Interface Defect Clustering on Field-Effect Mobility in SiC MOSFETs Investigated by Local Deep Level Transient Spectroscopy and Device Simulation. Materials Science Forum, 0, 1004, 627-634.	0.3	6
154	Development of nonlinear dielectric microscope and its application to measurement of ferroelectric polarization. , 0, , .		0
155	Surface Potential Fluctuations of SiO ₂ /SiC Interfaces Investigated by Local Capacitance-Voltage Profiling Based on Time-Resolved Scanning Nonlinear Dielectric Microscopy. Materials Science Forum, 0, 1062, 335-340.	0.3	2
156	Microscopic Evaluation of Al ₂ O ₃ /p-Type Diamond (111) Interfaces Using Scanning Nonlinear Dielectric Microscopy. Materials Science Forum, 0, 1062, 298-303.	0.3	1